

A Sub-Picosecond Digital Clock Monitoring System

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ABSTRACT: We describe a low-cost system designed to monitor wander in digital clocks with a precision of ≤ 1 ps. With this system we have shown that it is possible to track phase variations at the sub-picosecond level by adding noise to a reference clock. As in many cases where a clock is part of a complex distribution network small changes in temperature and other effects can lead to small changes in the a clock's phase. As a further demonstration of the system, we have used it to measure the phase changes induced in optical signals in fibers.

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1 Introduction

Systems that can distribute precision reference clocks stable to a level of a few picoseconds is a common theme in many current and proposed experiments in high energy physics. At the CERN High-Luminosity LHC (HL-LHC) the average number of interactions in each bunch crossing, ‘pile up’, will be ≈ 140 or higher. To help contend with this level pile up, both the ATLAS and CMS Collaborations are planning to install specialized detectors capable of measuring the arrival time of a particle to 30 ps or less.

For these detectors and others that exploit precision timing, both distributing and monitoring the stability of the reference clock will be an essential task. In this paper we describe a clock-monitoring system that we have developed to monitor drifts in the reference clock with sub-picosecond precision.

At the sub-picosecond level, the use of currently available frequency counters or time interval counters are precluded. One method for comparing two clocks employs a scheme known as the Dual Time-Difference Measurement circuit, where the clock signals are heterodyned and the beat clock used to extract the time difference[1]. A digital version of this circuit, the digital dual mixer time difference (DDMTD) circuit, was first proposed by Moriera and Darwazeh [2]. The circuit has recently been implemented in an FPGA[3] and with phase stabilization has achieved a level of ≈ 2 ps[4]. In this paper we report how we have used this approach with modern discrete RF components to design a system to measure variations in a clock’s phase to less than 100 fs.

In this report we describe the basic principle of operation of a DDMTD Circuit and report on results obtained from the laboratory measurements. We show that it is feasible to detect sub-picosecond phase variations with such a system.

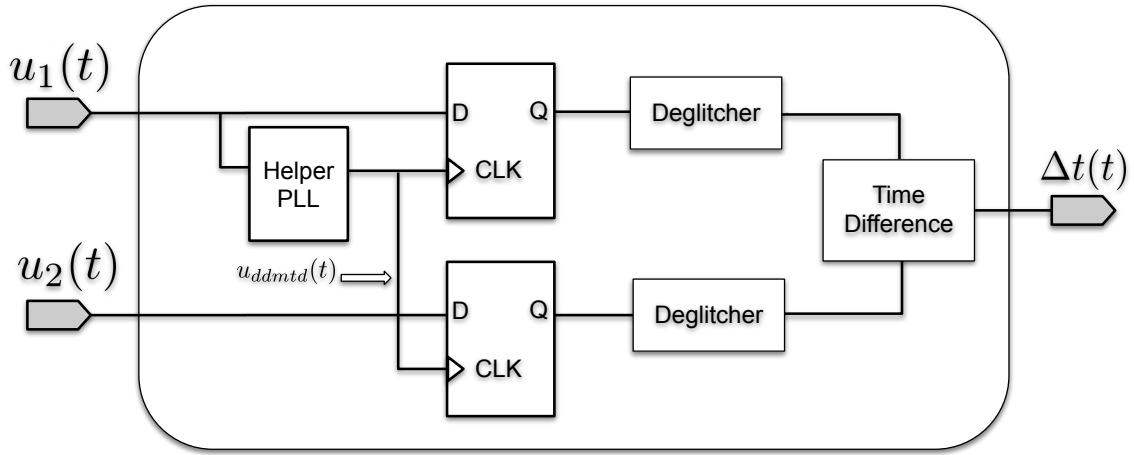


Figure 2.1: Schematic of DDMTD from Ref. [[2]]

2 Principle of Operation

The digital dual mixer time difference (DDMTD) is a digital circuit composed of a phase-locked-loop (PLL) and two flip-flops (FF) that can be used to compare the time interval error (TIE) of two clocks with high precision. The circuit is shown schematically in Figure 2.1. There are two input clocks, u_1 and u_2 , with frequencies ν_1 and ν_2 respectively; Where u_1 is the reference clock and u_2 is the test clock that is to be compared with the reference clock.

To track variations in phase between the two clocks a 'helper' PLL creates a new clock u_{ddmtd} that is phase-locked to u_1 and has a frequency (ν_{ddmtd}) that is slightly offset from ν_1 . The choice of the offset frequency is chosen using Equation (2.1):

$$\nu_{ddmtd} = \frac{N}{N+1} \cdot \nu_1 \quad (2.1)$$

Here N is an integer that determines the number of input clock cycles required for a full phase cycle of the heterodyned signal.

The input clocks, u_1 and u_2 , are compared by sampling them with two D-type Flip-Flops clocked on the positive edge of u_{ddmtd} . Whenever the phase between u_{ddmtd} and the input clock changes by some integer multiple of π , the output of the flip-flops will change state, tracking the integrated time difference over a period of N/2 cycles of u_{ddmtd} clock. The resulting output of the flip-flops will form a clock with beat frequency given by Equation (2.2). The phases of these beat clocks will directly depend on the relative phases of clocks u_1 and u_2 and their frequency given by:

$$\nu_{beat} = \frac{1}{N} \cdot \nu_{ddmtd} = \frac{1}{N+1} \cdot \nu_1 \quad (2.2)$$

The integrated time difference between two clock edges can then be measured after N/2 input clock cycles with a minimum precision given by Equation (2.3).

$$\Delta t_{min} = \frac{1}{\nu_{ddmtd}} \cdot \frac{\nu_{beat}}{\nu_1} = \frac{t_{ddmtd}}{N+1} = \frac{t_1}{N} \quad (2.3)$$

Here, the $v_1/v_{ddmtd} = N + 1$ is the effective temporal gain (T_g) of the DDMTD. By measuring the difference between the two beat clocks, the phase difference between u_1 and u_2 can be measured to a precision given by Equation (2.4). [2]

$$\Delta t = \Delta t_{beat} \cdot \frac{v_{beat}}{v_1} = \frac{\Delta t_{beat}}{N + 1} \quad (2.4)$$

Here, Δt_{beat} is the time difference between the transitions of the two beat clocks and Δt is the time difference between the input clocks. Since T_g is directly proportional to N , the limit of the temporal gain depends on how close of a frequency the helper PLL can accurately generate with respect to the input clock frequency.

For the results reported in this paper, we have used digital input clocks with a frequency of 160MHz and $N=100k$ or $10k$, with a theoretical precision of $62.5fs$ and $625fs$ respectively.

As the Time Interval Error (TIE) is determined from both the positive and negative edges of the beat clocks, the highest frequency that can be measured is given by Equation (2.5), with v_{max} approximately $1.6kHz$ and $16kHz$ for $N=100k$, and $10k$ respectively.

$$v_{max} < \frac{2_{pos-negedge} \times v_{beat}}{2_{NyquistLimit}} = \frac{v_1}{N + 1} \quad (2.5)$$

When the u_{ddmtd} has a transition edge close to the transition edge of the input clocks, the set-up and hold times will be violated and the output of the flip-flop becomes unstable. This instability can last for several clock cycles of the input clock. To estimate the exact time of the transition, the average of the time of the first and last transitions can be used. The length of this instability is determined by the setup and hold times of the flip-flops used. Standard CMOS devices have setup and hold times of ~ 800 ps, while for the silicon-germanium NB7V52M flip-flops used in the circuit discussed below, they are ~ 15 ps, thus the exact time of the transition can be more accurately estimated.

3 System Design

The clock-monitoring system that we developed to investigate the precision that can be achieved is shown in Figure 3.1. It is based on a 5u motherboard, which supports a Nexys Video board and a Raspberry Pi, with the DDMTD circuit mounted in a mezzanine board connected to the Nexys Video board via an FMC connector. The Raspberry Pi manages the configuration of the on-board electronics and the data acquisition from the Artix-7 FPGA on the Nexys Video board. The beat clocks from the DDMTD mezzanine card are sampled by the FPGA and stored in memory until the Raspberry Pi starts data acquisition.

A schematic of the DDMTD mezzanine is shown in Figure 3.2. The circuit is equipped with four high-performance flip-flops (FF) ¹, which has a maximum clocking rate of 12GHz and a Silicon Labs Si5344 Jitter Attenuator / Clock Multiplier IC that has a quoted rms jitter of 90fs². The choice of duplicating the two input flip-flops was to allow the investigation of the properties and stability of the flip-flops

¹NB7V52M, manufactured by ON-Semiconductors

²<https://www.silabs.com/documents/public/data-sheets/Si5345-44-42-D-DataSheet.pdf>

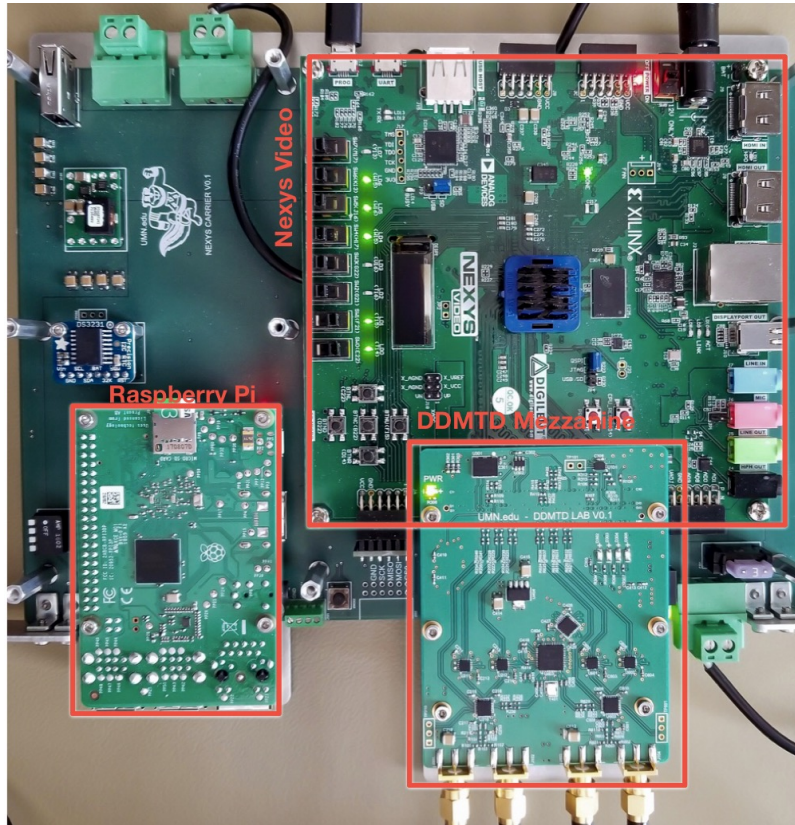


Figure 3.1: DDMTD Nexys Board

The two input clocks are fed into the mezzanine board as differential pairs on SMA connectors. The clocks are fanned out to the four flip-flops and to the Si5344 using the 1-to-6 fan-out chip NB7VQ1006M from On Semiconductor. These fan-outs are high-performance with a typical RJ(Random Jitter)+DJ(Deterministic Jitter) = (0.2 + 3.0) ps.³ The differential D-type flip-flop NB7V52M has an RMS jitter < 0.8ps.⁴ The output of the helper PLL Si5344 is distributed to the clock inputs of all the flip-flops using a second NB7VQ1006M. A copy of this clock (CLK PLL) is transmitted to the Artix-7 FPGA to drive the sampling logic in the FPGA.

The firmware logic implemented on the Artix-7 FPGA is shown in Figure 3.3. Two FIFOs are used to store the value of a 32-bit counter, which is incremented by the CLK PLL. Whenever the beat clocks, Q1A and Q1B, changes state the value of the counter is pushed to the FIFO. When the FIFO chain is almost full, the Raspberry Pi pulls the data through the SPI bus and sends it to the PC via Ethernet.

Offline a Fast Fourier Transform (FFT) is used to determine the frequency components of the jitter. The exact time of the phase transition between the two clocks is estimated from the difference between the first and the last edges of the meta-stable region.

³<https://www.onsemi.com/pub/Collateral/NB7VQ1006M-D.PDF>

⁴<https://www.onsemi.com/pub/Collateral/NB7V52M-D.PDF>

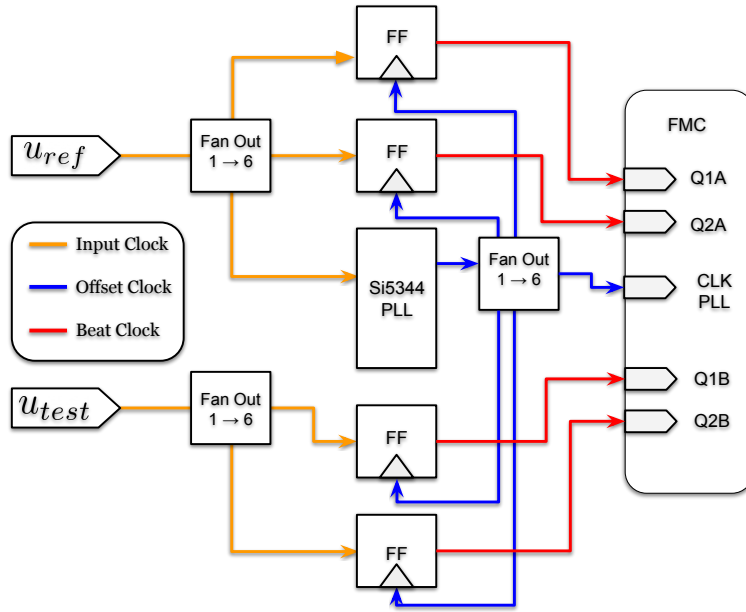


Figure 3.2: Schematic of the DDMTD Mezzanine. The clocks u_{ref} and u_{test} are fed into flip flops that are clocked by an offset clock generated by a SI5344 Jitter Attenuator / Clock Multiplier. The outputs of the flip-flops are sent via the FMC connector to the Artix-7 FPGA on the Nexys video board.

4 Characterizing System Performance by Injecting Noise

To investigate the performance of the DDMTD and to measure the precision with which TIE can be measured, sinusoidal jitter patterns were injected onto a 160 MHz digital clock. For this a 160 MHz clock was generated by a pulse pattern generator⁵, and jitter was injected onto one of them using a secondary function generator⁶ connected to the Delay Control Input of the pulse generator. While the nominal amplitude of the jitter generated by the function generator for a 1V input signal was 25ps, all our measurements were consistent with $\sim 12\%$ calibration error, such that a 1V signal produced a ~ 28 ps jitter.

The injected jitter pattern was compared to the jitter pattern recovered using the DDMTD-Nexys Board. The schematic of the configuration used for the tests is shown in Figure 4.1. With this set up we were able to investigate sinusoidal jitter injection patterns with amplitudes between 0.25 ps and 25 ps and frequencies up to 6 kHz.

We tested two values for the offset parameter (as defined in Equation (2.1)) $N = 100,000$ and $N = 10,000$ which corresponds to a ν_{max} of 1.6kHz and 16kHz at a carrier clock frequency of 160MHz.

Figure 4.2 shows the results from the DDMTD for a injected sinusoidal variation of 50 Hz at a noise amplitude of 25ps. We observe the 50Hz signal and its higher monotonics in the FFT.

⁵Keysight 81134A

⁶Aim TTI TG5011A

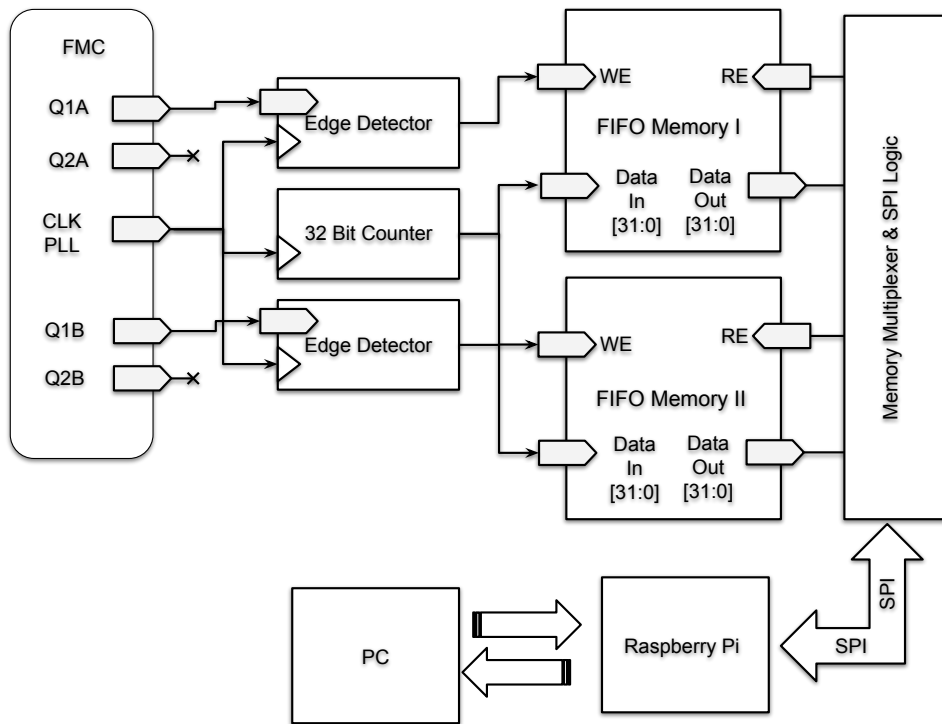


Figure 3.3: Schematic of the FPGA Logic

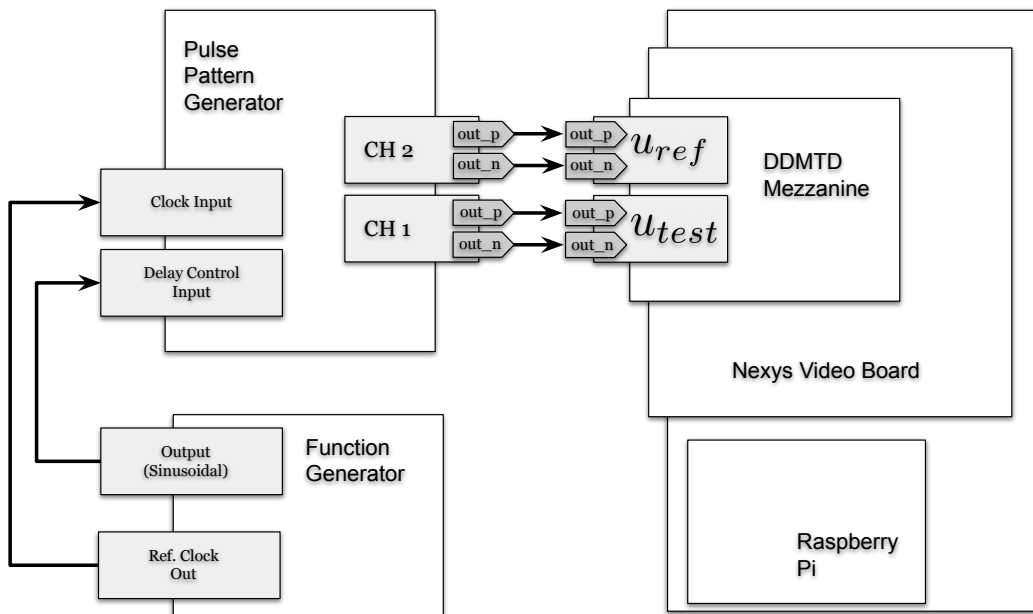


Figure 4.1: Clock and jitter injection system used in the characterization of the DDMTD.

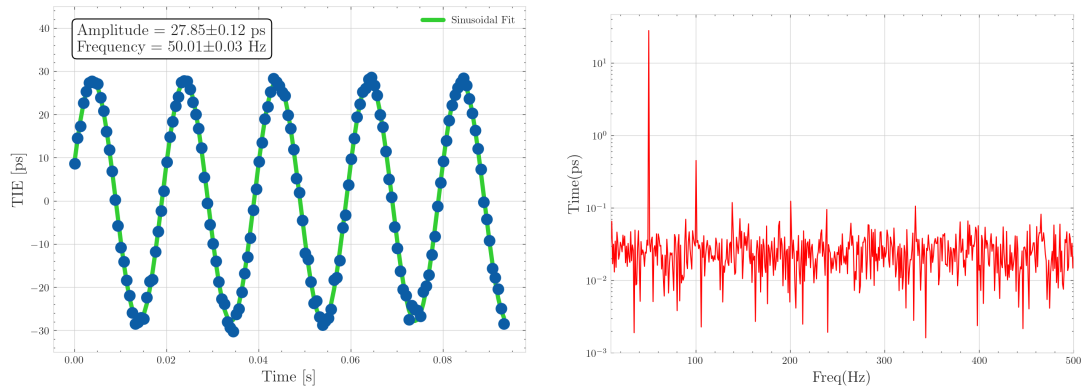


Figure 4.2: Left: Time Interval Error recovered when a harmonic 50 Hz jitter with an amplitude of 28 ps is injected onto a 160MHz digital clock. Right: FFT of the TIE signal recovered where the peak at 50Hz and higher monotonics can be seen.

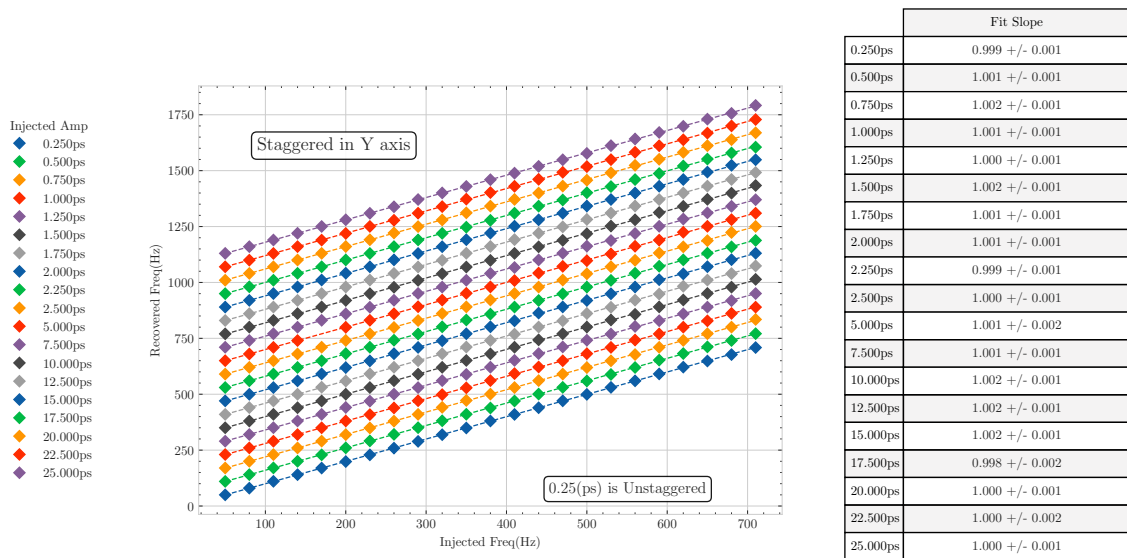


Figure 4.3: Recovered Noise Frequency vs Injected Noise Frequency 0.25 to 25 ps; N=100k

Figure 4.3 shows the response of the system when the input jitter was modulated from 40 Hz to 750 Hz with amplitudes ranging from 0.25 ps to 25 ps, and Figure 4.4 shows the system's response when N was set to 10,000. In both cases the response is linear.

Similar observations are shown made in Figures 4.5 to 4.7, where the recovered noise amplitudes were compared against the injected noise amplitudes.

The response of the DDMTD system to different frequencies of injected noise are shown in Figures 4.8 to 4.10 and is observed to be flat across all the injected frequencies with a maximum standard deviation less than 100fs.

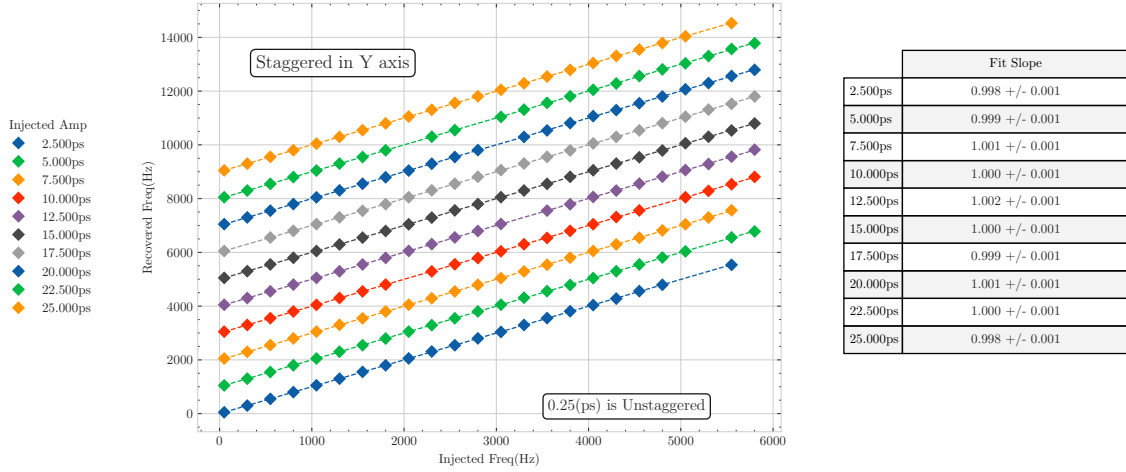


Figure 4.4: Recovered Noise Frequency vs Injected Noise Frequency 2.5 to 25 ps; N=10k

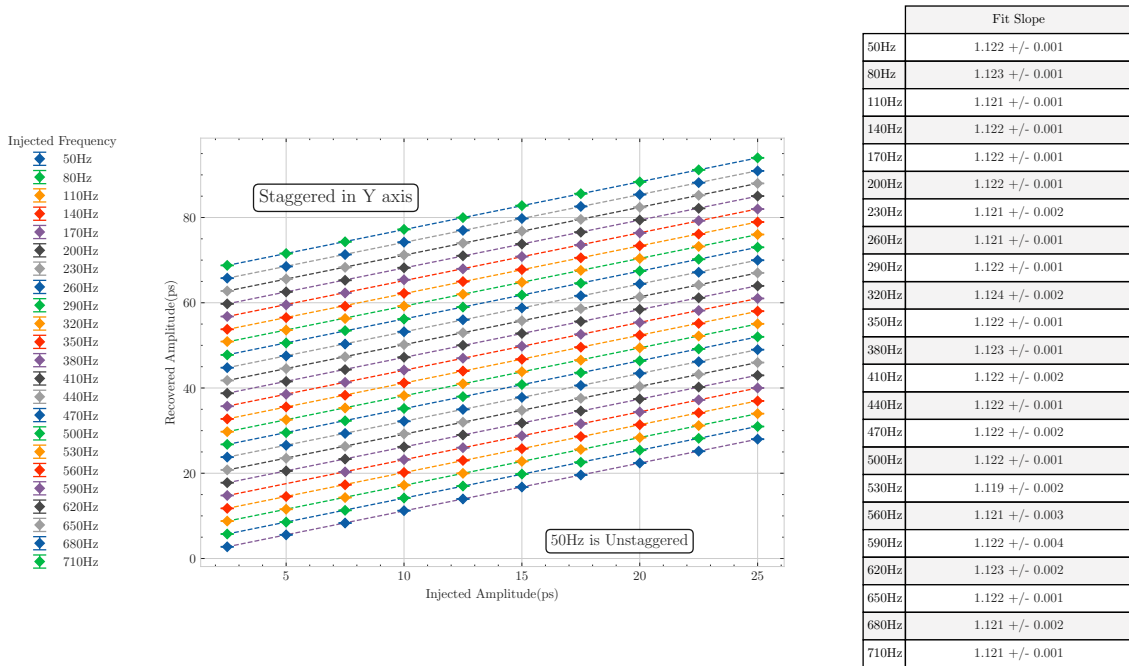


Figure 4.5: Recovered Noise Amplitude vs Injected Noise Amplitude 2.5 to 25 ps; N=100k

5 Measurements made with the DDMTD

5.1 Effects of temperature on Front-End Electronics and Optical Fiber

We used the clock-monitoring system to investigate temperature effects in transmission optical fibers and in a front-end emulator with an LpGBT and a VTRx+ optical transceiver. The schematic of the test system is shown in Figure 5.1.

For these tests we used an Si5345 jitter attenuator as the source of a stable 40MHz clock that was transmitted to a front end electronics emulator through a custom designed board, FLY 640[5],

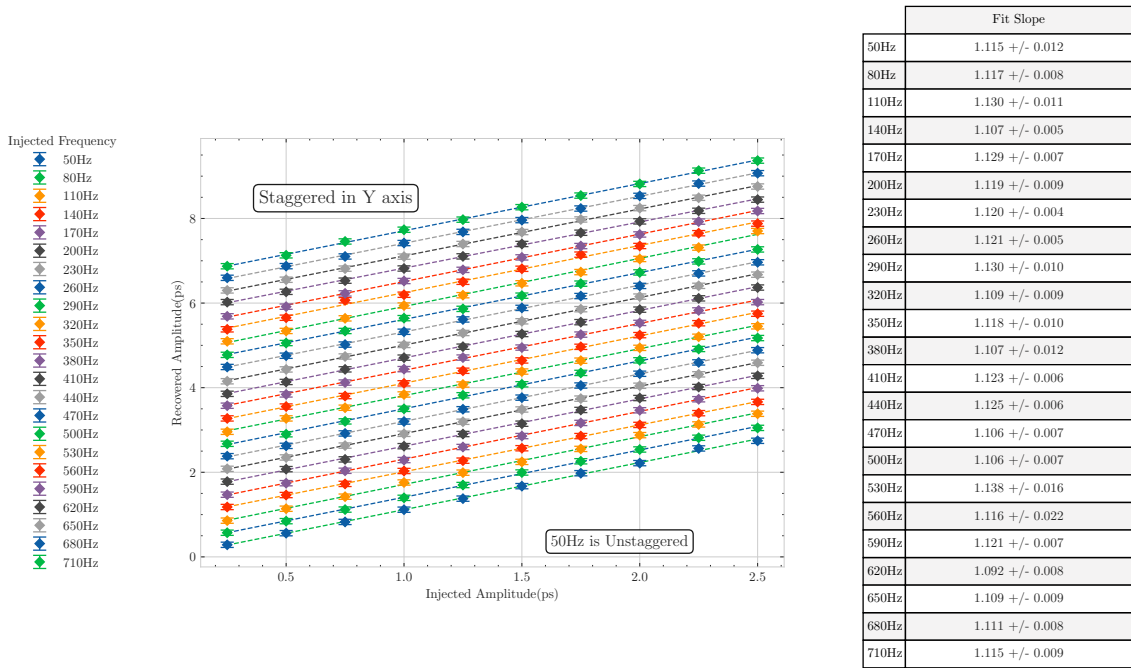


Figure 4.6: Recovered Noise Amplitude vs Injected Noise Amplitude 0.25 to 2.5 ps; N=100k. The plots are staggered in Y-axis for the readability.

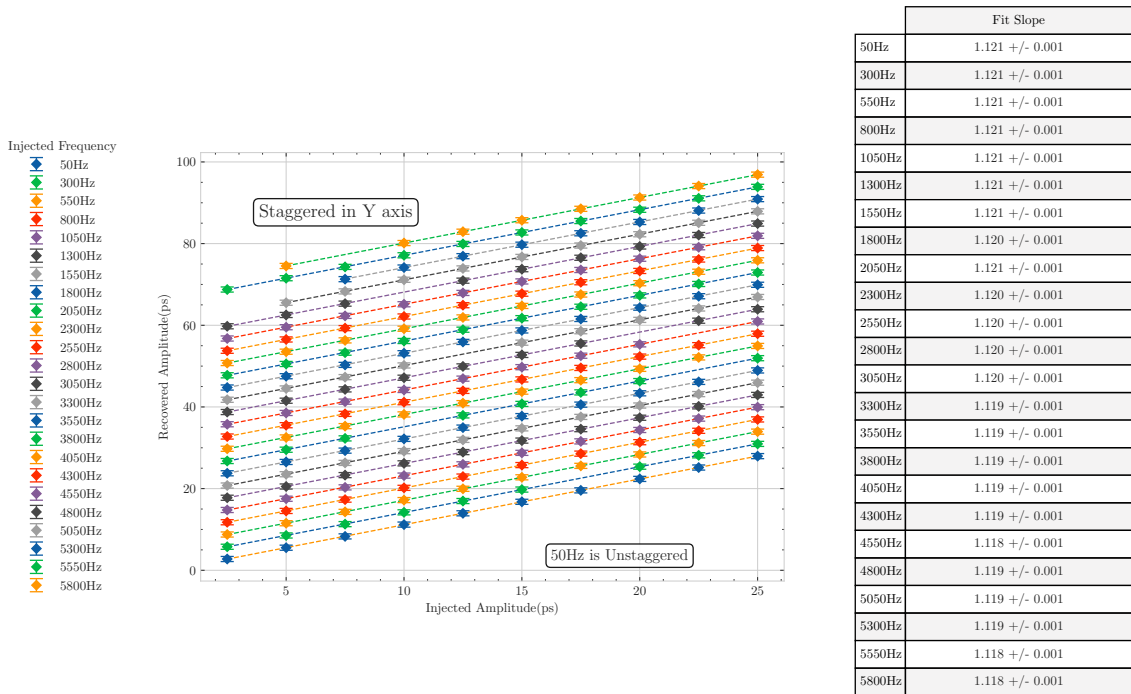


Figure 4.7: Recovered Noise Amplitude vs Injected Noise Amplitude 2.5 to 25 ps; N=10k

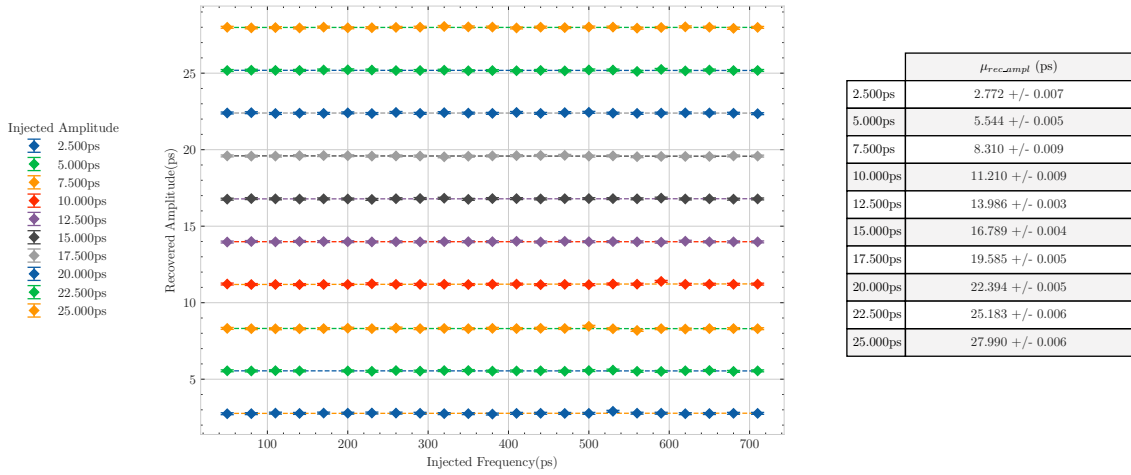


Figure 4.8: Stability across frequency 2.5 to 25 ps; N=100k

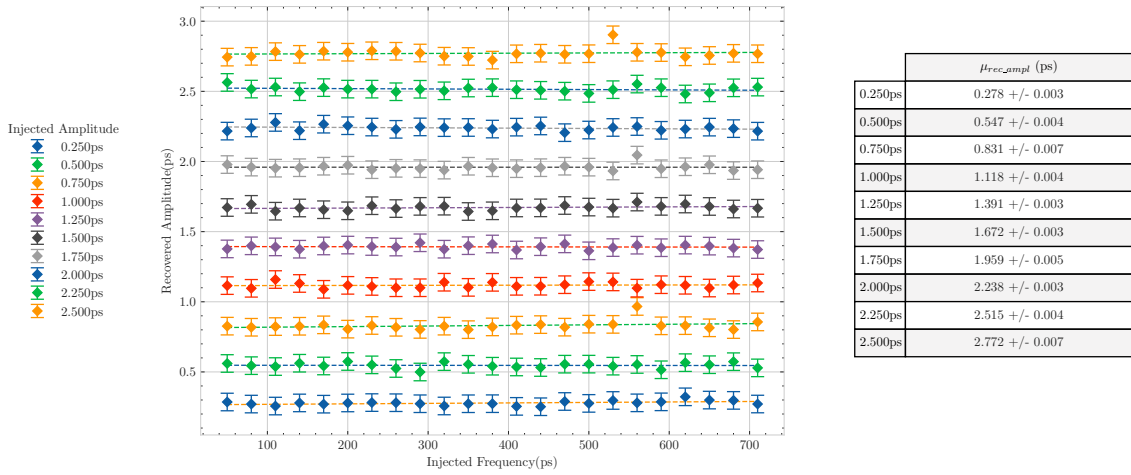


Figure 4.9: Stability across frequency 0.25 to 2.5 ps; N=100k

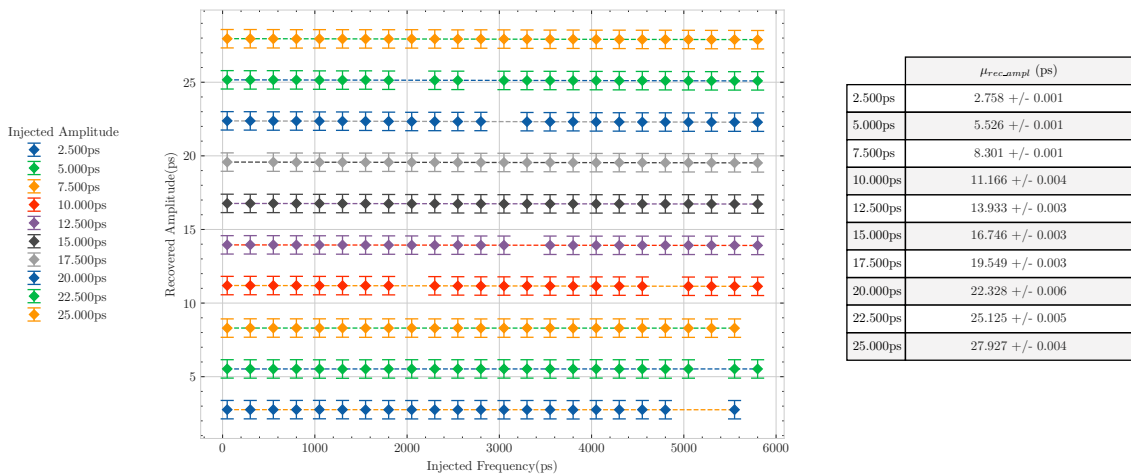


Figure 4.10: Stability across frequency 2.5 to 25 ps; N=10k

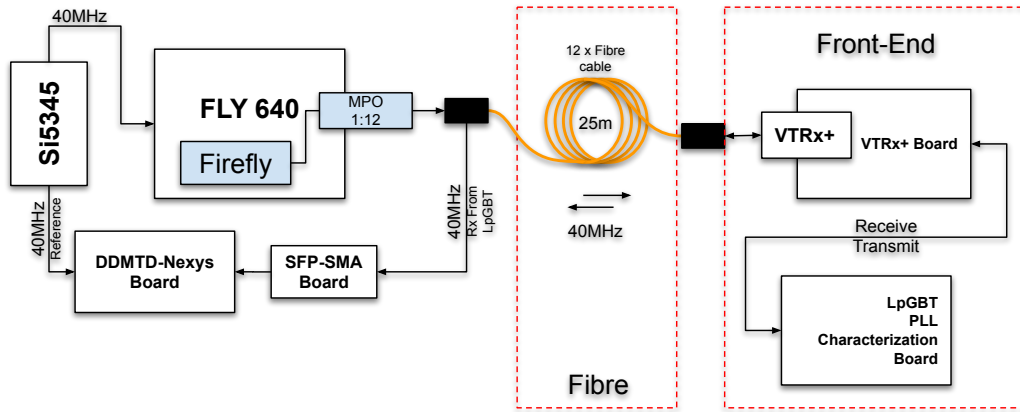


Figure 5.1: Configuration to measure temperature effects on the Fiber Optics, and the Front-End of the Clock Distribution System

on a 25m long 12-channel multimode optical fiber. The front end emulator, consisting of a VTRX+ and an LpGBT characterization board, returned the 40MHz clock signal back through the optical fiber to the DDMTD clock-monitoring system. A copy of the 40MHz was also sent from the Si5344 board directly to the DDMTD as the reference clock.

With this setup, we measured the temperature effects on a 25 m optical fibre and on the front-end emulator by separately placing them inside a climate chamber. The parts of the set up that were kept inside the chamber are shown in Figure 5.1.

Compared to our qualification tests discussed above, the carrier frequency was 40MHz rather than 160MHz. At this frequency, with $N=100k$, only jitter frequencies up to 400Hz are detectable, which is nevertheless much faster than any effects expected from temperature changes.

First test was performed with the up-link and down-link fibres in the temperature-controlled chamber, the clock-monitoring system was used to track phase variations as the fiber temperature was changed. The results of these tests are shown in Figure 5.2a. We observe a phase change of $\approx 4 \text{ ps}/^\circ\text{C}$. Assuming that the up-link and down-link shifts are symmetric, we measure the phase change of an optical clock signal propagating in multi-mode fiber to be $\approx 0.08 \text{ ps}/\text{m}\cdot^\circ\text{C}$.

In the second test we investigated the effect of temperature changes on the front-end emulator. Figure 5.2b shows the effect of temperature on the the LpGBT and the VTRx, with temperatures ranging from -30°C to 60°C in steps of 10°C . Assuming a symmetric up-link and down-link phase shift, we observe a delay coefficient of $\approx 1.3 \text{ ps}/^\circ\text{C}$.

These results are consistent with the measurements made with the digital oscilloscopes and a Phase Noise Analyser.

5.2 Tests with a Pure Clock Distribution System

As part of our investigation into the problem of distributing a precision clock we have designed and tested a scalable pure clock distribution system using high-performance, low-jitter, off-the-shelf components. Full details of the system may be found in Ref. [5]. In the system, a 640 MHz low-jitter digital clock is generated and distributed to two distribution boards, where copies of the

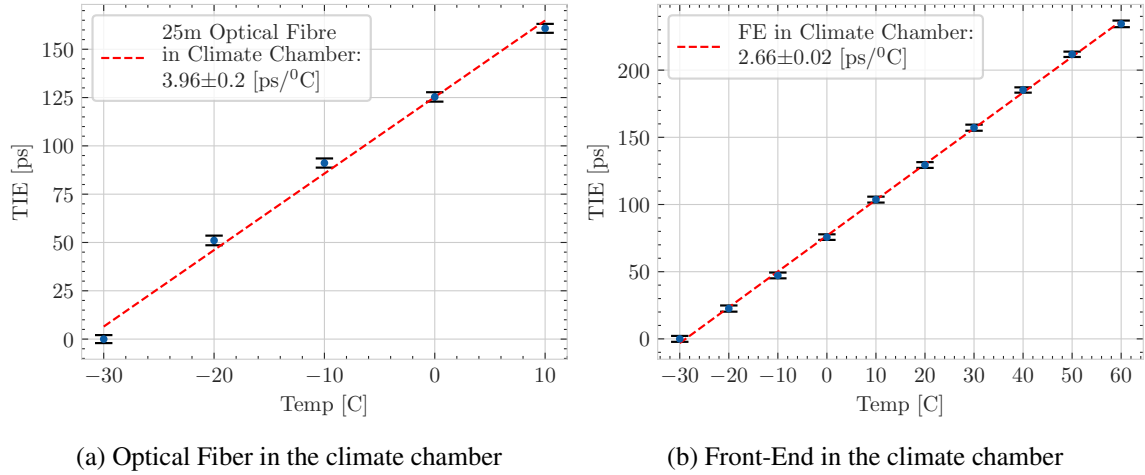


Figure 5.2: Temperature effects on fibers and a front-end emulator measured with the clock-monitoring system.

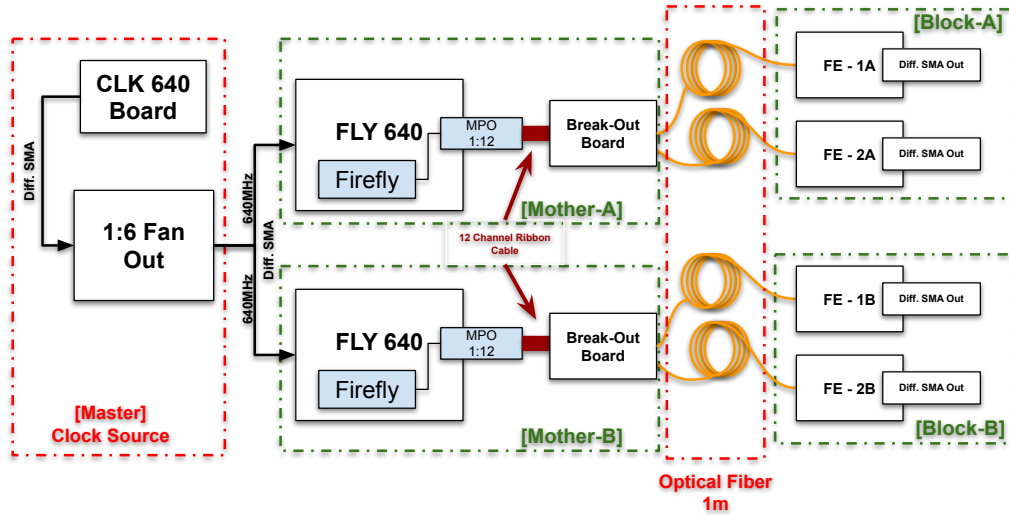


Figure 5.3: Schematic of the Pure Clock Distribution System

clock are made using 1-6 fan-out and distributed using 12-channel SAMTEC Firefly Tx modules. The optical signal from the Fireflies is sent via 100 m long multi-mode fibers to front-end emulator boards (FE), where the optical signal is converted back to an electrical signal and divided by four and made available on SMC connectors. The system is shown schematically in Figure 5.3.

We report here on tests made with this system using the DDMTD clock monitor. These tests were made with $N=10,000$ and $100,000$. The maximum frequency of the jitter that we are sensitive to is 16kHz with $N=10\text{k}$, and 1.6kHz with $N=100\text{k}$ for a clock frequency of 160MHz .

We measured the noise floor of the Si5344 in the "Master" by comparing two output clocks

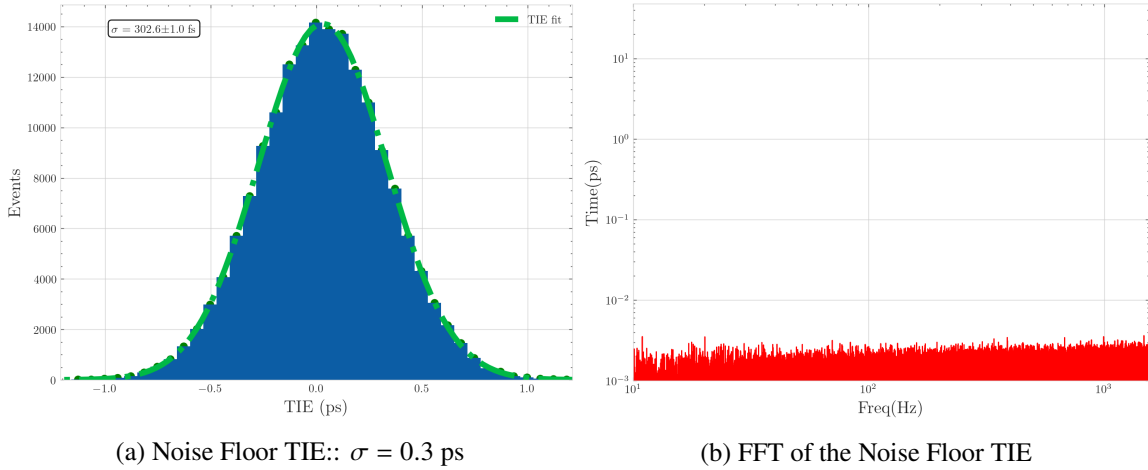


Figure 5.4: DDMTD Measurement of the Noise Floor for N=100,000 at 160MHz

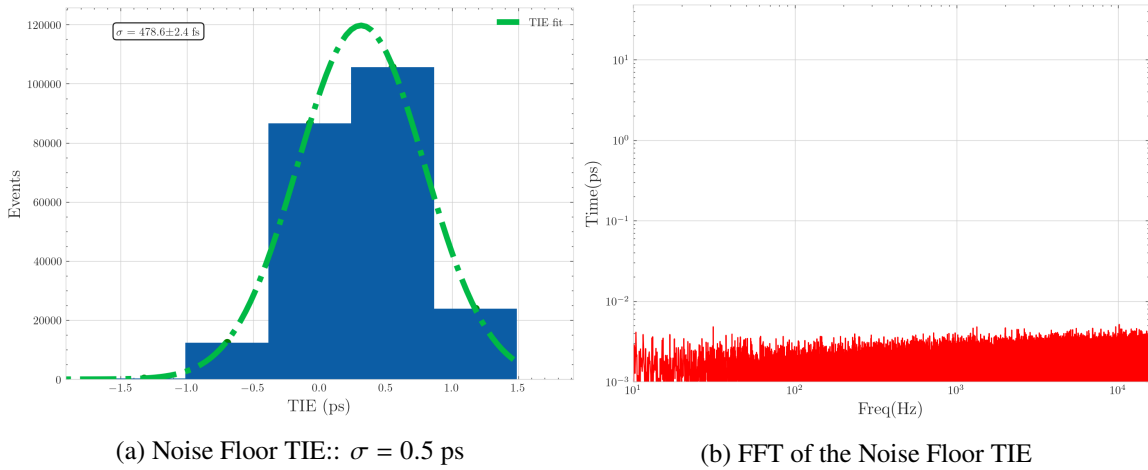


Figure 5.5: DDMTD Measurement of the Noise Floor for N=10,000 at 160MHz

set at 160 MHz with the DDMTD. The results for N = 100k and 10k are shown in Figures 5.4 and 5.5. The standard deviations obtained were 0.3 ps and 0.4 ps for 100K and 10K respectively. In both cases the noise level in the frequency domain were flat between 1 Hz and the upper limit of the measurement, 1.6 kHz for N = 100k and 16 kHz for N = 10k.

Measurements were made comparing the clock outputs from the FE boards that were supplied by the same FLY 640 boards. The comparisons were FE-1A compared to FE-2A, and FE-1B compared to FE-2B shown in Figures 5.6 to 5.8. Comparing clocks distributed from separate distribution boards, FE-1A and FE-1B and FE-2A and FE-2B, which is comparable to how two references clocks could be distributed in an experiment, we obtained the TIE distributions shown in Figures 5.10 to 5.12. The summary of the measurements are provided in Table 1.

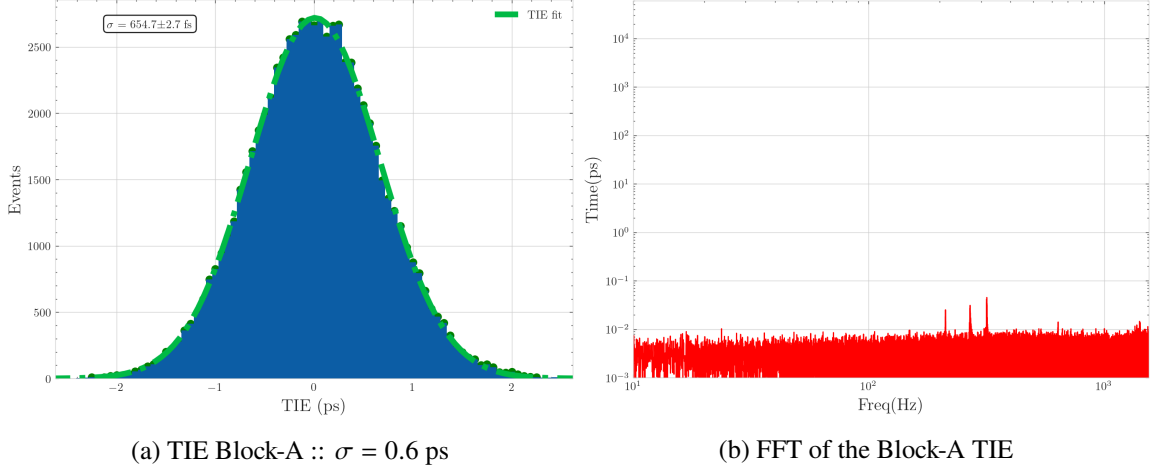


Figure 5.6: DDMTD Measurement between outputs of Block-A for N=100,000 at 160MHz

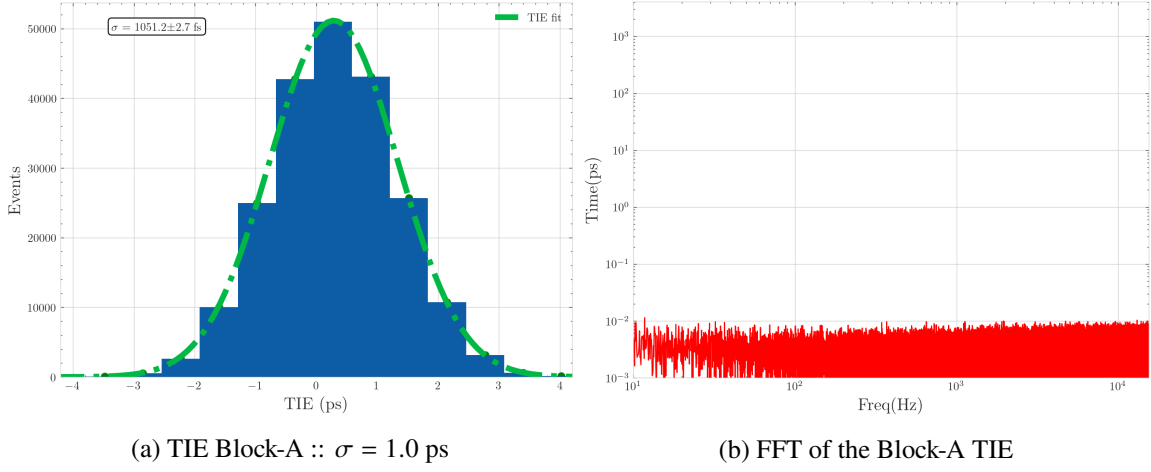


Figure 5.7: DDMTD Measurement between outputs of Block-A for N=10,000 at 160MHz

u_1	u_2	σ_{TIE} (ps)	
		N=10k	N=100k
Master-1	Master-2	0.5	0.3
FE-1A	FE-2A	1.0	0.6
FE-1B	FE-2B	0.8	0.5
FE-1A	FE-1B	0.8	0.5
FE-2A	FE-2B	1.1	0.6

Table 1: Measurements on the Pure Clock Distribution System using DDMTD Circuit

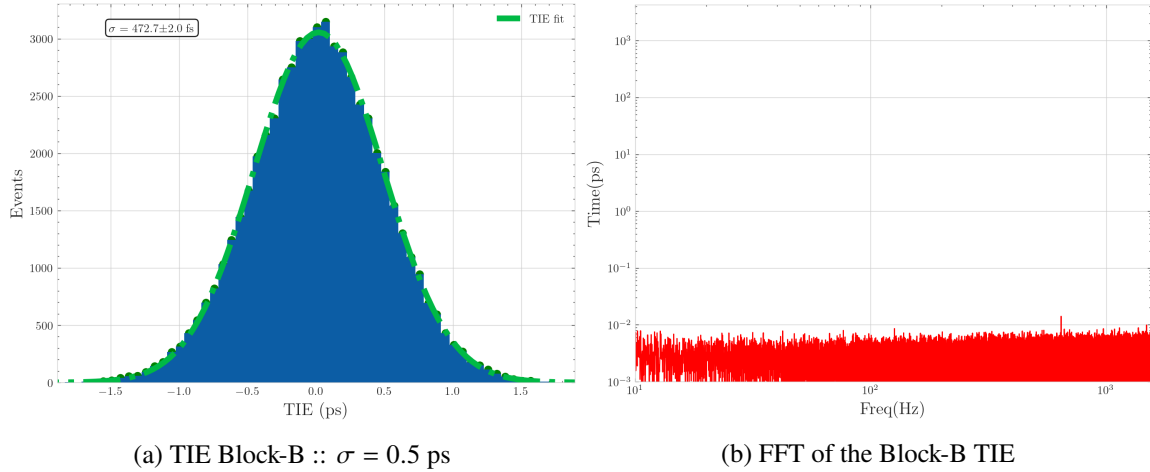


Figure 5.8: DDMTD Measurement between outputs of Block-B for N=100,000 at 160MHz

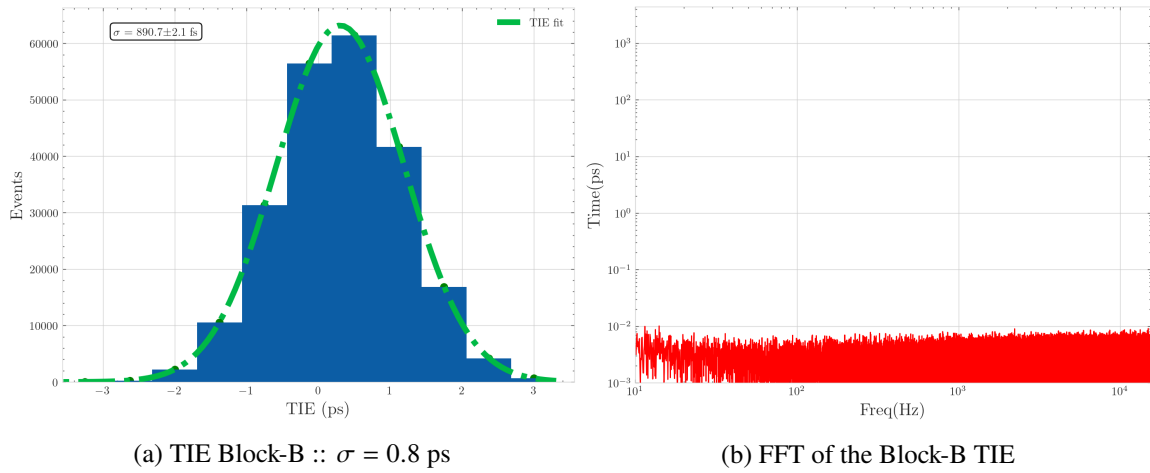
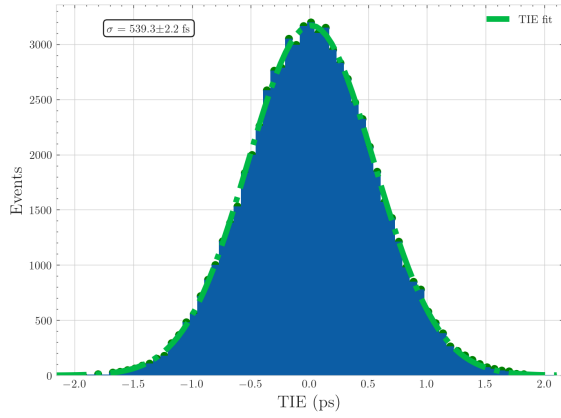


Figure 5.9: DDMTD Measurement between outputs of Block-B for N=10,000 at 160MHz

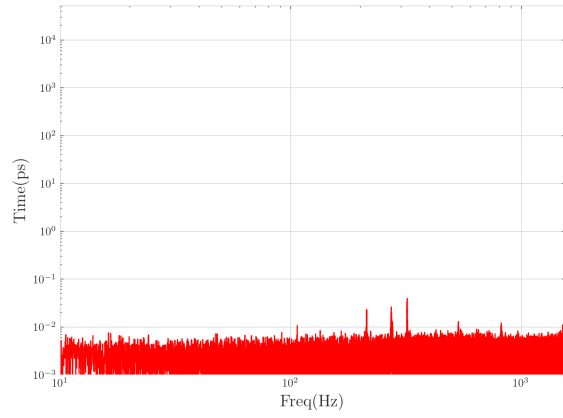
6 Summary

The DDMTD was characterised by injecting sinusoidal noise with frequency ranging from 50Hz to 710Hz in the case of N=100,000 and 50Hz to 5800Hz in the case of N=10,000. The observations made from both the cases yielded results indicating the accuracy and stability of the DDMTD that are very promising. We were able to recover the noise frequency from the injected jitter with a maximum deviation of 0.2%. The recovered amplitudes are systematically shifted by $\approx 12\%$ and the recovered amplitudes of the jitter are found to be stable across different injected frequencies of noise with a maximum standard deviation less than 100fs.

Tests made with a pure clock distribution system shows a maximum standard deviation of 1.1ps between FE-2A and FE-2B (sensitivity up to 16kHz). This value is consistent with the measurement made between FE-1A and FE-2A in Block-A.

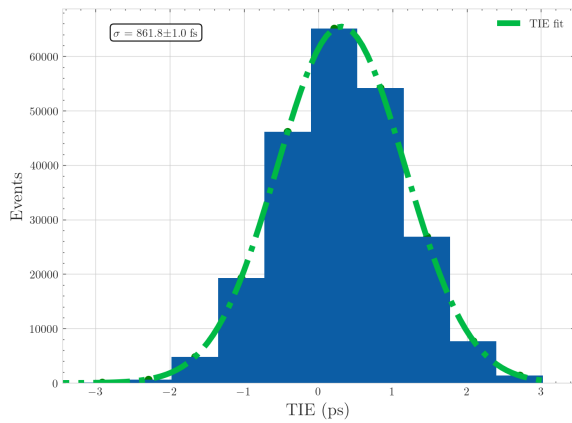


(a) TIE :: $\sigma = 0.5$ ps

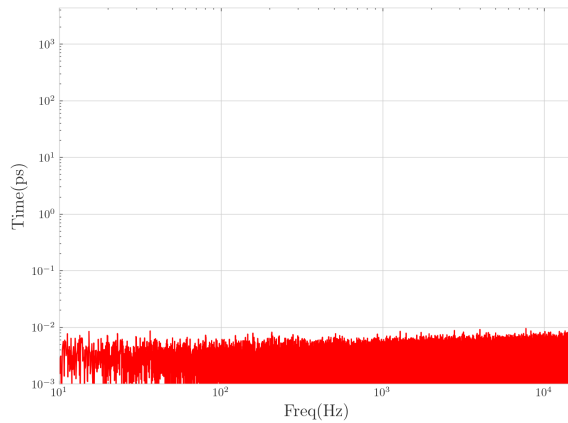


(b) FFT of the TIE

Figure 5.10: DDMTD Measurement between outputs of FE-1A and FE-1B for N=100,000 at 160MHz



(a) TIE :: $\sigma = 0.8$ ps



(b) FFT of the TIE

Figure 5.11: DDMTD Measurement between outputs of FE-1A and FE-1B for N=10,000 at 160MHz

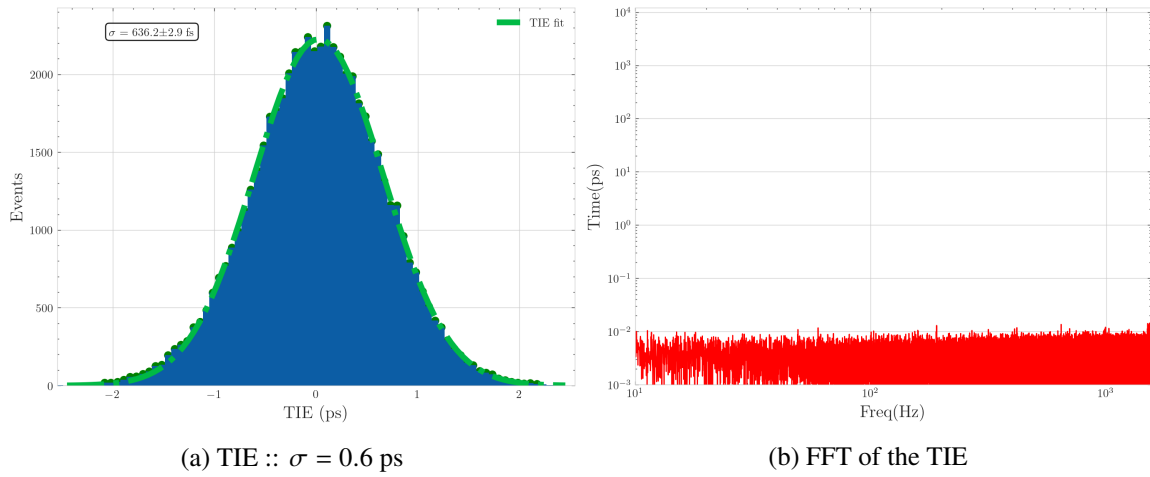


Figure 5.12: DDMTD Measurement between outputs of FE-2A and FE-2B for N=100,000 at 160MHz

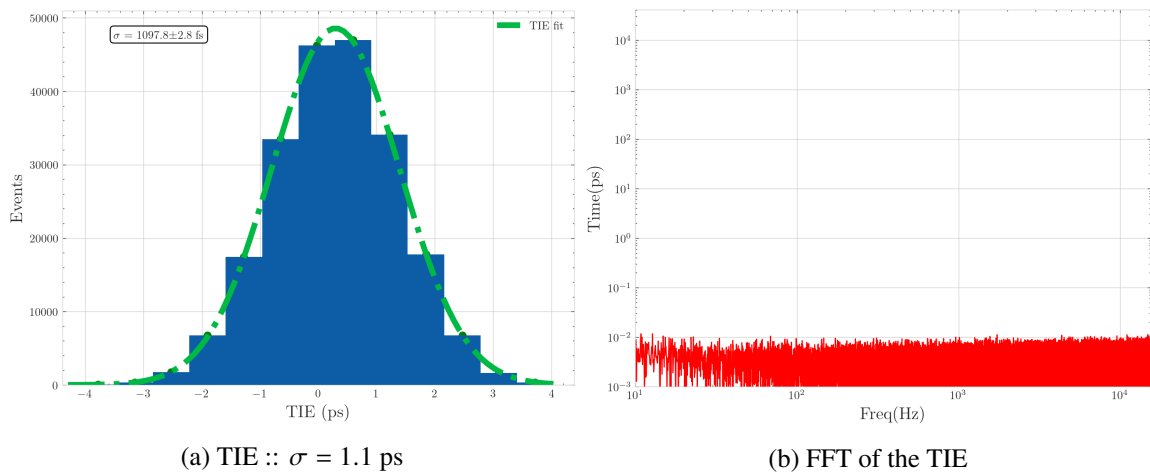


Figure 5.13: DDMTD Measurement between outputs of FE-2A and FE-2B for N=10,000 at 160MHz

Acknowledgments

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References

- [1] D.W. Allan and H. Daams, *Picosecond time difference measurement system*, in *29th Annual Symposium on Frequency Control*, pp. 404–411, 05, 1975, [DOI](#).
- [2] P. Moreira and I. Darwazeh, *Digital femtosecond time difference circuit for CERN's timing system*, 2011.
- [3] E.B.D.S. Mendes, S. Baron and M. Taylor, *TCLink: A Timing Compensated High-Speed Optical Link for the HL-LHC experiments*, *PoS TWEPP2019* (2020) 057.
- [4] E. Mendes, S. Baron, C. Soos, J. Troska and P. Novellini, *Achieving Picosecond-Level Phase Stability in Timing Distribution Systems With Xilinx Ultrascale Transceivers*, *IEEE Trans. Nucl. Sci.* **67** (2020) 473.
- [5] R. Rusack, J. Brashear, E. Frahm, S. Jain and R. Saradhy, *A Precision Pure Clock Distribution System*, *PoS TWEPP2019* (2020) 056.